

8.701

Introduction to Nuclear
and Particle Physics

Markus Klute - MIT

10. Instrumentation

2. Tracking Detectors



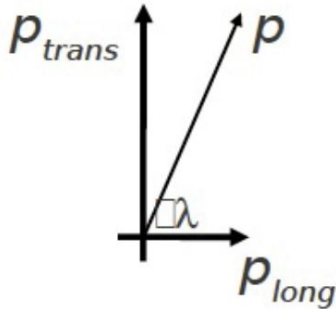
Momentum Measurement

Charged particles are deflected by magnetic fields

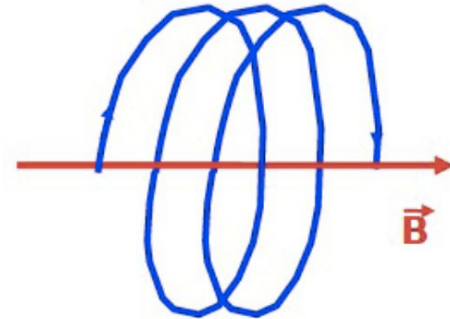
- Homogeneous B-field particle follows a circle with radius r

$$p_t [\text{GeV}/c] = 0.3 \cdot B [\text{T}] \cdot r [\text{m}]$$

- Particle with longitudinal momentum component follow a helix

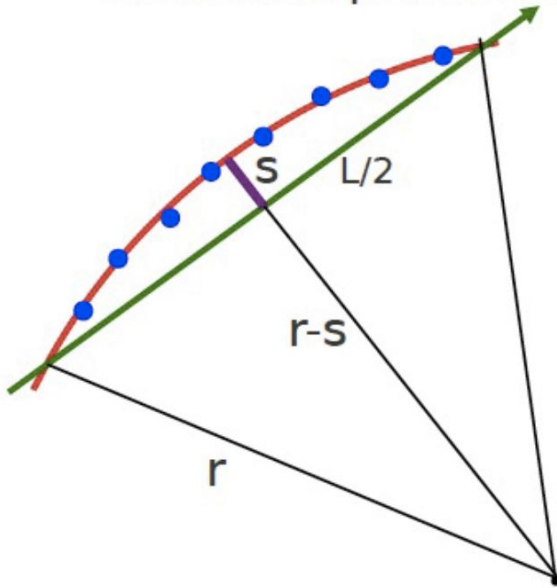


$$p = \frac{p_t}{\sin \lambda}$$



Momentum Measurement

- Tracking detectors measure the position of the charged particle on various points along the helix (circle)



$$r = \frac{L^2}{8s} + \frac{s}{2} \quad \text{if } L \gg s \quad r \approx \frac{L^2}{8s}$$

$$\sigma_s = \sqrt{\frac{A'_N}{N+4}} \frac{\sigma_{r\phi}}{8}$$

Gluckstern formula
Nucl. Inst. Meth.
24(1963) 381

$$A'_N = 720$$

$$\frac{\sigma_{p_t}}{p_t} = \frac{8p_t}{0.3BL^2} \cdot \sigma_s$$

$$\frac{\sigma_{p_t}}{p_t} \propto p_t$$

Momentum Measurement

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NUCLEAR INSTRUMENTS AND METHODS 24 (1963) 381-389; NORTH-HOLLAND PUBLISHING CO.

UNCERTAINTIES IN TRACK MOMENTUM AND DIRECTION, DUE TO MULTIPLE SCATTERING AND MEASUREMENT ERRORS*

R. L. GLUCKSTERN

Physics Department, Yale University, New Haven, Connecticut

Received 23 March 1963

Momentum Resolution

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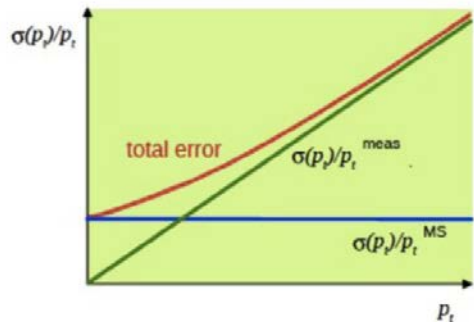
Dominated by two components

- Contribution from measurement error $\frac{\sigma_{p_t}}{p_t} \propto p_t$

- Contribution from multiple scattering $\Theta_0 \propto \frac{1}{p_t} \sqrt{\frac{L}{X_0}}$

$$\frac{\sigma_{p_t}}{p_t} \propto p_t \cdot \sigma_{r\phi}$$

- Multiple scattering contribution to transverse momentum error is constant!



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Wire Chambers

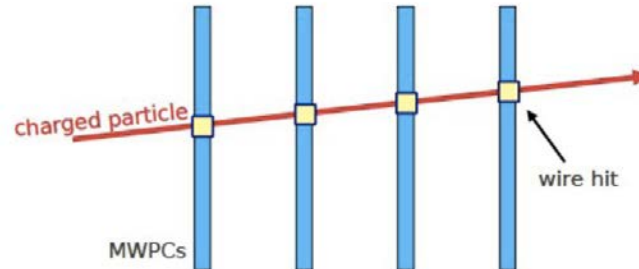
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Multi Wire Proportional Chamber

- Was first electronic device allowing high statistics experiments
- With reasonable resolution

Typically several 100-1000 wires, 1mm spacing

- Hit on wire give 2d track measurement
- Signal on wire for 3d measurement (or using stereo wires)
- Resolution: $\sigma_x \approx \frac{d}{\sqrt{12}}$ e.g. for $d=1$ mm; ~ 300 μm resolution

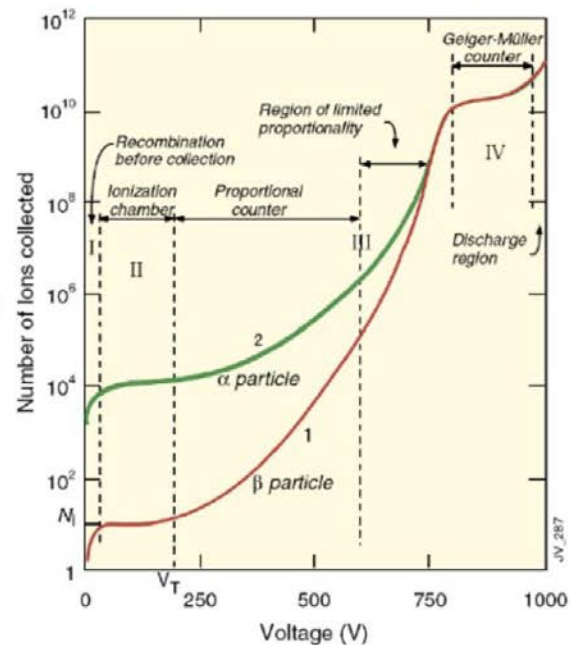


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Wire Chambers

High Voltage

- No collection (I)
 - Ions recombine before collected
- Ionization mode (II)
 - Ionization charge is fully collected, no charge multiplication yet
 - Gain ~ 1
- Proportional mode (IIIa)
 - Gas multiplication, signal on wire proportional to original ionization
 - Gain $\sim 10^4$
- Limited Proportional Mode (IIIb)
 - Secondary avalanches created by photoemission from primary avalanches, signal no longer proportional
 - Gain $\sim 10^{10}$
- Gaiger mode (IV)
 - Massive photoemission + discharge, stopped by HV breakdown

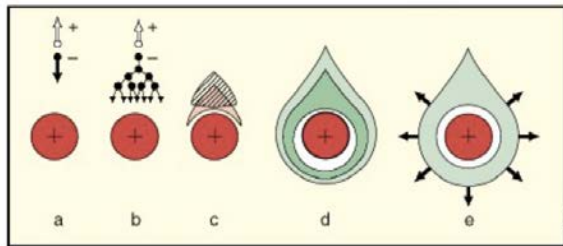


Wire Chambers

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Signal formation is different to what you may think

- Electrons from avalanche are collected within a few ns
- Contribution of electrons to wire signal only a few %



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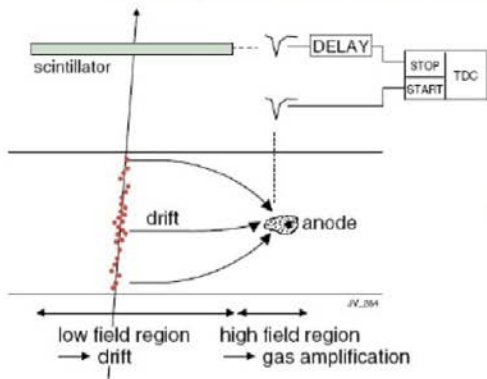
Main part of signal comes from ions

- Ions drift back to cathode over long distance (mm-cm) and time (μs -ms)
- Moving ions charge creates signal via influence (mirror charge in conductor)

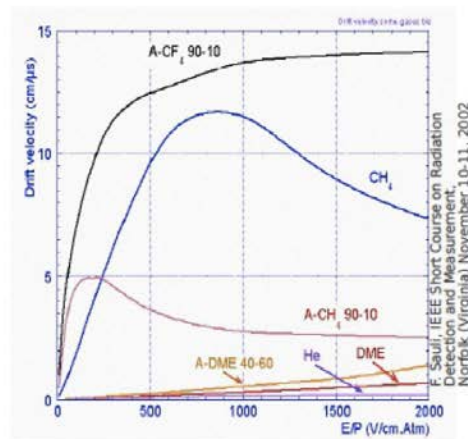
Wire Chambers

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- Resolution limited by wire spacing
 - Better resolution, shorter wire spacing, more wires, larger wire forces and strong electrostatic forces when wires are close to each other
- Solution
 - Obtain position information from drift time
 - Drift time = time between primary ionization and arrival on wire



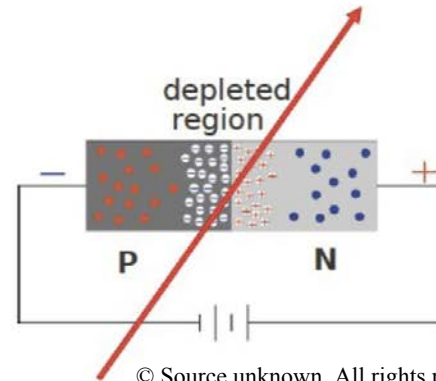
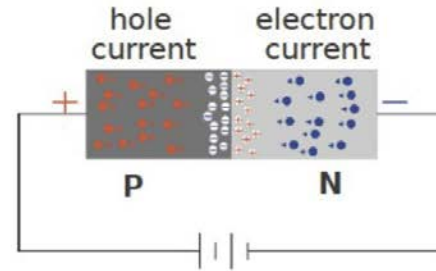
$$s = \int_{t_{start}}^{t_{stop}} v_D dt$$



Solid state tracking detectors

Basic element of a solid state (silicon) detector is ... a diode

- p-type (more holes) and n-type (more electrons) doped silicon material is put together.
- for use as particle detector diode needs to be connected in opposite way.
- Around junction of p- and n-type material depletion region is created.
- Charged particle can create new electron/hole pairs in depletion area sufficient to create a signal.



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